

Notice of References Cited	Application/Control No. 10/606,633	Applicant(s)/Patent Under Reexamination HECK ET AL.	
	Examiner Hoa C. Nguyen	Art Unit 2841	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,876,056	04-2005	Tilmans et al.	257/528
*	B	US-2003/0047799	03-2003	Cheever et al.	257/686
*	C	US-6,713,314	03-2004	Wong et al.	438/25
*	D	US-6,891,239	05-2005	Anderson et al.	257/414
*	E	US-6,914,323	07-2005	Curtis et al.	257/682
*	F	US-6,559,530	05-2003	Hinzel et al.	257/684
*	G	US-6,384,353	05-2002	Huang et al.	200/181
*	H	US-6,900,773	05-2005	Poilasne et al.	343/795
*	I	US-6,853,067	02-2005	Cohn et al.	257/704
*	J	US-6,426,484	07-2002	Hembree et al.	219/209
*	K	US-2005/0024165	02-2005	Hsu, Wan-Thai	333/186
*	L	US-2004/0262645	12-2004	Huff et al.	257/232
*	M	US-2004/0012464	01-2004	Ma et al.	333/193

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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